

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/577,325 NAKAMURA ET AL.	
		Examiner	Art Unit	Page 1 of 1 Matthew W. Such 2891

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,429,040	08-2002	Bao et al.	438/99
*	B	US-6,861,664	03-2005	Ong et al.	257/40
*	C	US-6,720,572	04-2004	Jackson et al.	257/40
*	D	US-6,420,057	07-2002	Ueda et al.	428/690
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Klauk, H., et al. "Contact Resistance in Organic Thin Film Transistors." SOLID-STATE ELECTRONICS, Vol. 47 (2003): pp. 297-301.
	V	Babel, A. and Jenekhe, S.A. "High Electron Mobility in Ladder Polymer Field Effect Transistors." J. AM. CHEM. SOC., Vol. 125 (2003): pp. 13656-13657.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.